

BERTScope S with Live Data Option Wins Best Supporting Solution Award at the Network Systems Design Conference

Menlo Park, Calif., Nov 2 – SyntheSys Research, an innovator in high-speed signal integrity test and measurement solutions, won the Best Supporting Solution Award for its BERTScope™ S Analyzer with Live Data Option at the 2005 Network Systems Design Conference. Awards were given during the recent NSDC conference, held in San Jose earlier this month. Entries were judged on product innovation, overall technology, and potential market impact. Judges for this fourth annual awards program included Linley Gwennap, principal analyst for the Linley Group, Bob Wheeler, analyst for the Linley Group, Dave Bursky, Editor-at-large for Electronic Design Magazine, and Craig Matsumoto, a senior editor for Light Reading.

Network Systems Design Conference highlights the latest in cutting edge technology, with its Best of Show Awards program honoring the latest accomplishments in the industry. The BERTScope S Analyzer with Live Data Option is a prime example of industry innovation, enabling the full suite of physical layer analysis; Jitter Peak, BER Contour, Q-factor and mask testing. The BERTScope S, offers the addition of stressed eye, a critical jitter measurement capability for testing today's computer, storage, enterprise and telecommunications standards.

“Often overlooked, the challenge of testing and verifying the high-speed data streams has been met by the BERTScope signal analyzer developed by SyntheSys Research,” said one judge, Dave Bursky, Editor-at-large for Electronic Design Magazine. “It offers an impressive set of features that let designers perform deep physical-layer analysis and capture rare physical events that traditional oscilloscopes cannot capture.”

About BERTScope™

BERTScope™ is a trademark of SyntheSys Research, Inc., design and manufacturers advanced digital channel error analysis instruments to telecom, enterprise, storage and computer markets. SyntheSys Research is a privately held California corporation founded in 1989 with the mission to develop new, advanced test instruments in high-speed electronics. SyntheSys' patented BitAlyzer® error location analysis™ provides detailed information including pattern-dependent error histograms, enabling engineers to discover the source of errors. For further information, call (650) 364-1853 or visit our website at www.BERTSCOPE.com.

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